



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of:

Chen et al.

§

Group Art Unit: 1746

Serial No. 10/712,460

§

Examiner: To be determined

Filed: 11/13/2003

§

Customer No.: 000042717

For: Semiconductor Wafer

§

Attorney Docket No.:

Manufacturing Methods

§

TSMC2002-1015/24061.42

Employing Cleaning Delay Period

§

SECOND INFORMATION DISCLOSURE STATEMENT

Mail Stop Amendment  
Commissioner For Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Dear Sir:

In compliance with the duty of disclosure under 37 CFR §1.56, and in accordance with the practice under 37 CFR §1.97 and §1.98, the Examiner's attention is directed to the documents listed on the enclosed modified Form PTO-1449. No inference should be made that the cited references are in fact material, are in fact prior art, or that no better art exists. The cited patents are listed in numerical order and are not in any order based on their pertinence.

The above-identified application was filed after June 30, 2003. Therefore, pursuant to the waiver of the requirement under 37 CFR 1.98 (a)(2)(i) as stated in a Pre-OG Notice dated July 11, 2003, only a copy of the non-patent literature document listed on the enclosed modified Form PTO-1449 is attached.

This Information Disclosure Statement is being filed within three months of the United States filing date or before the mailing date of a first Office Action on the merits. No certification or fee is required (37 CFR §1.97(b)).

It is respectfully requested that the above information be considered by the Examiner and that a copy of the enclosed Form PTO-1449 be returned indicating that such information has been considered.

Respectfully submitted,

David M. O'Dell  
Registration No. 42,044

Date: 10-7-04  
HAYNES AND BOONE, LLP  
901 Main Street, Suite 3100  
Dallas, Texas 75202-3789  
Telephone: 972-739-8635  
Facsimile: 214-200-0853  
R87496.1

Certificate of Mailing

I hereby certify that this correspondence is being deposited with the United States Postal Service as first class mail in an envelope addressed to Commissioner For Patents, P.O. Box 1450, Alexandria, VA 22313-1450 on 10-7-04.

  
Bonnie E. Boyle

<p>In place of PTO-1449 Form</p> <p><b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b> <i>(use as many sheets as necessary)</i></p>				<p>U. S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE</p> <p><i>Complete if Known</i></p>	
				Application Number	10/712,460
				Filing Date	11/13/2003
				Applicant(s)	Chen et al.
				Art Unit	1746
				Examiner Name	To Be Determined
SHEET	1	OF	1	Attorney Docket Number	TSMC2002-1015/24061.42

FOREIGN PATENT DOCUMENTS					
Examiner's Initials	Cite No.	Foreign Patent Document (Country Code - Number - Kind)	Publication Date MM-DD-YYYY	Patentee or Applicant of Cited Document	Translation Y/N

NON-PATENT LITERATURE		
Examiner's Initials	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article, title of the item, date, page(s), volume-issue number(s), publisher, city/country where published
	AC	Decoupled Plasma Nitridation (DPN), May 2001, Foresight, Pages 43-45. -

Examiner Signature		Date Considered	
-----------------------	--	--------------------	--

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include a copy of this form with next communication to applicant.